# Lecture-9 Chemical Vapor Deposition

#### **Two-Dimensional Nanostructures Cont...**

(Ref: Guozhong Cao; Nanostructures & Nanomaterial: Synthesis, Properties & Applications)

# **Chemical Vapor Deposition (CVD)**

- Substrate Exposed to Volatile Precursors
- Precursors react/decompose on substrate
- Desired film/powder deposited on substrate
- Extensively studied and well documented
- Close association with solid-state micro-electronics

# **Typical Chemical Reactions**

• Homogeneous & Heterogeneous reactions are

intricately mixed.

• Gas phase homogeneous reaction prevails:

(i) Increasing Temperature

(ii) Partial Pressure of Reactants

• Gas phase reactions predominates with:

(i) Extremely high concentration of Reactants

- It leads to Homogeneous Nucleation
- For good quality films deposition:

- Homogeneous nucleation should be avoided.

#### Chemical reactions can be grouped into:

(A) Pyrolysis or thermal decomposition

 $SiH_4(g) \rightarrow Si(s) + 2H_2(g)$  at 650°C

 $Ni(CO)_4(g) \rightarrow Ni(s) + 4CO(g)$  at 180°C

(B) Reduction

 $SiCl_4(g) + 2H_2(g) \rightarrow Si(s) + 4HCl(g)$  at 1200°C

 $WF_6(g) + 3H_2(g) \rightarrow W(s) + 6HF(g) \text{ at } 300^{\circ}C$ 

(C) Oxidation

 $SiH_4(g) + O_2(g) \rightarrow SiO_2(s) + 2H_2(g)$  at 450°C

 $4PH_3(g) + 5O_2(g) \rightarrow 2P_2O_5(s) + 6H_2(g) \text{ at } 450^{\circ}C$ 

(D) Compound Formation

 $SiCl_4(g) + CH_4(g) \rightarrow SiC(s) + 4HCl(g)$  at 1400°C

 $TiCl_4(g) + CH_4(g) \rightarrow TiC(s) + 4HCl(g)$  at 1000°C

(E) Disproportionation

 $2\text{Gel}_2(g) \rightarrow \text{Ge}(s) + \text{Gel}_4(g) \text{ at } 300^\circ\text{C}$ 

(F) Reversible Transfer

 $As_4(g) + As_2(g) + 6GaCl(g) + 3H_2(g)$ 

 $\rightarrow$  6GaAs(s) + 6HCl(g) at 750°C

- Demonstration of versatile chemical nature of CVD
- For deposition of given film
  - Different reactants/precursors can be used
  - Different chemical reactions may apply
- E.g.
  - Silica films may be synthesized by different ways:

### Different ways to achieve silica-film:

- a) SiH<sub>4</sub>(g) + O<sub>2</sub>(g)  $\rightarrow$  SiO<sub>2</sub>(s) + 2H<sub>2</sub>(g)
- b) SiH<sub>4</sub>(g) + 2N<sub>2</sub>O(g)  $\rightarrow$  SiO<sub>2</sub>(s) + 2H<sub>2</sub>(g) + 2N<sub>2</sub>(g)
- c) SiH<sub>2</sub>Cl<sub>2</sub>(g) + 2N<sub>2</sub>O(g)  $\rightarrow$  SiO<sub>2</sub>(s) + 2HCl(g) + 2N<sub>2</sub>(g)

- d)  $Si_2Cl_6(g) + 2N_2O(g) \rightarrow SiO_2(s) + 3Cl_2(g) + 2N_2(g)$

e) Si(OC<sub>2</sub>H<sub>5</sub>)<sub>4</sub>(g)  $\rightarrow$  SiO<sub>2</sub>(s) + 4C<sub>2</sub>H<sub>4</sub>(g) + 2H<sub>2</sub>O(g)

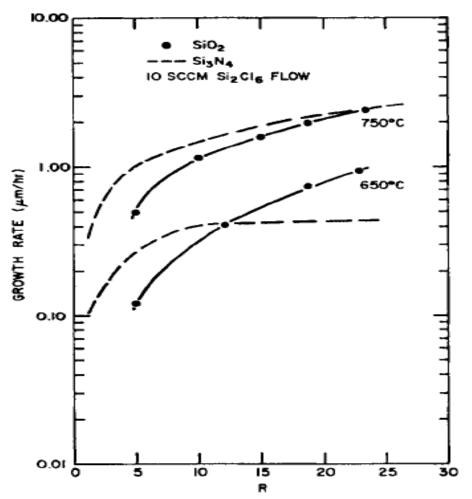
- From same precursors and reactants
  - Different films can be deposited
  - By varying
    - (i) Ratio of reactants &
    - (ii) Deposition conditions

For example:

• Mixture of  $Si_2Cl_6$  &  $N_20$ 

may deposit

- Silica films, and
- Silicon Nitride films



Deposition rates of silica and silicon nitride as functions of the ratio of reactants and deposition conditions. *Ref: R.C. Taylor and B.A. Scott, J. Electrochem. Soc., 136*(1989)2382.

## **Reaction kinetics**

• Although CVD is nonequilibrium process

- Controlled by

(i) Chemical kinetics, &

(ii) Transport phenomena

• Equilibrium analysis is still useful

- In understanding the CVD process

- Chemical reaction & phase equilibrium determine:
  - Feasibility of particular process, and
  - Final state attainable
- In a given system
  - Multistep complex reactions are involved

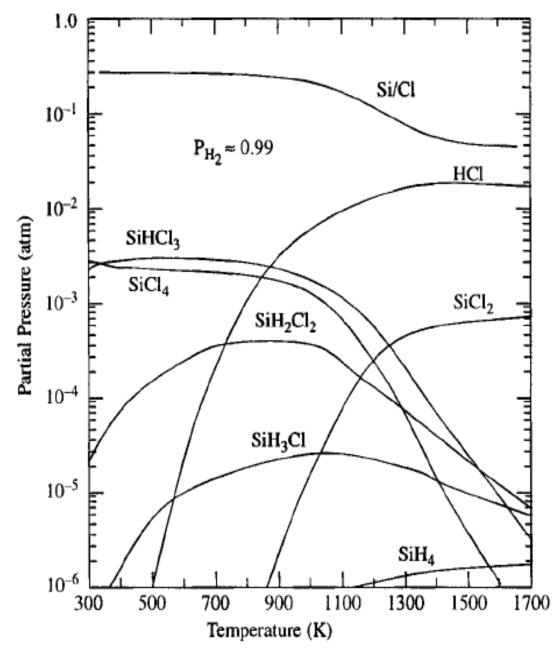
Fundamental reaction pathways & kinetics

- Investigated for few industrial important systems

- Complexity of reaction pathways & Kinetics arises:
  - In seemingly simple system, &
  - Deposition process
- Let's take an example of:
  - Reduction of chlorosilane by hydrogen

- In Si-CI-H system, at least 8 gaseous species exist:
  - SiCl<sub>4</sub>, SiCl<sub>3</sub>H , SiCl<sub>2</sub>H<sub>2</sub>, SiClH<sub>3</sub>,
  - SiH<sub>4</sub>, SiCl<sub>2</sub>, HCl and H<sub>2</sub>
- These 8 species are in equilibrium under:
  - Deposition conditions governed by

(i) Six equations of chemical equilibrium



Composition of gas phase as a function of reactor temperature for a molar ratio of Cl/H=0.01 and a total pressure of 1 atm, calculated using the available thermodynamic data. *Ref: E.Sirtl, L.P.Hunt, and D.H.Sawyer, J. Electrochem. Soc., 121(1974)919.* 

# **Transport Phenomena**

- Transport phenomena plays critical role in CVD
- Governs access of film precursors to substrate
- Influences reactions taking place before deposition
  - Degree of desirable &
  - Unwanted gas phase reactions

- Characteristics of CVD chambers have:
  - Complex reactor geometries, &
  - Large thermal gradient characteristics
- Leads to variety of flow structures & affect:
  - Film Thickness
  - Compositional Uniformity, &
  - Impurity Levels

- For most CVD systems
  - Characteristic Pressure ≥ 0.01 atm
  - Mean Free Paths >> Characteristic System

Dimension

- Lower gas velocities ~ tens of cm/s
- Reynolds number < 100
- Flows are laminar

- During deposition of CVD Film:
  - Stagnant boundary layer of thickness ( $\delta$ )
  - Adjacent to growth surface is developed
- In boundary layer,
  - Concentration of growth species decreases
  - From bulk concentration, Pi
  - To surface concentration, *Pio* (above growing film)

Growth species diffuses through boundary

- Prior to depositing onto growth surface

- In CVD, gas composition is reasonably dilute
- Diffusion flux through boundary layer is:

$$\mathsf{J}_{\mathsf{i}} = \frac{\mathsf{D}(\mathsf{P}_{\mathsf{i}} - \mathsf{P}_{\mathsf{io}})\mathsf{RT}}{\delta}$$

(For gas/ growth species)

- 'D' is diffusivity in expression & depends on
  - Pressure and Temperature
- 'D' can be expressed as:

 $\mathsf{D} = \mathsf{D}_0 \left(\frac{\mathsf{P}_0}{\mathsf{P}}\right) \left(\frac{\mathsf{T}}{\mathsf{T}_0}\right)^{\mathsf{n}}$ 

- n is experimentally found to be ~ 1.8
- D<sub>o</sub> is value of D measured at

- Standard temperature T<sub>o</sub> (273 K), and

- Pressure  $P_o$  (1 atm)

• D<sub>o</sub> depends on gas composition

- For deposition of large area films (above growth surface)
  - Depletion of growth species or reactants
  - Results in non-uniform film deposition
- To overcome non-uniformity in deposited films
  - Various reactor designs are developed
  - It improves gas-mass transport (through boundary layer)
- E.g. Low pressure, New Design, Substrate Susceptor

- Several CVD methods & reactors are developed
  - Depending on types of precursors used
  - Deposition conditions applied, and
  - Forms of energy introduced to system
- To activate desired chemical reactions
  - For deposition of solid films on substrates

- For example, when precursors used are:
  - Metal-organic compounds
  - Process is referred as MOCVD (Metalorganic)
- When plasma is used to promote chemical reaction
  - It is plasma enhanced CVD or PECVD

There are many other modified CVD methods

Such as,

- LPCVD (low pressure CVD)
- Laser enhanced or assisted CVD, and
- Aerosol-assisted CVD or AACVD

- LPCVD differs from conventional CVD
- Low gas pressure of -0.5 to 1 torr is used
- Low pressure is to enhance
  - Mass flux of gaseous reactants & products
  - Through boundary layer between

# Laminar gas stream and substrates

• In PECVD processing,

- Plasma is sustained within chambers

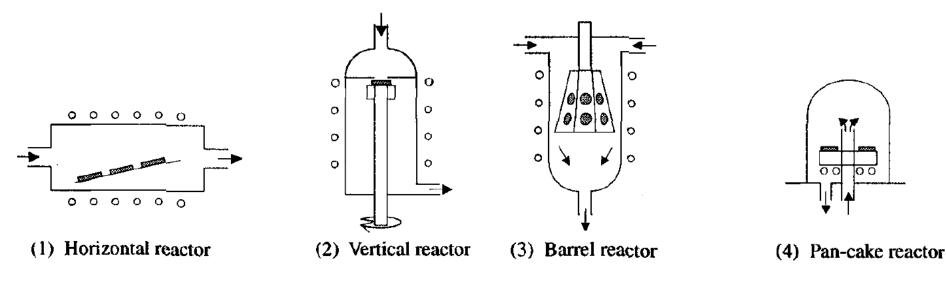
- Simultaneous CVD reactions occur
- Typically, the plasma are excited either by
  - RF field (Frequencies: 100 kHz to 40 MHz)

(Gas pressures: 50 mtorr to 5 torr)

- Microwave (Frequency ~ 2.45 GHz)

- CVD reactors are generally divided into
  - Hot-wall CVD, and
  - Cold-wall CVD

Figure depicts a few common setups of CVD reactors



A few common setups of CVD reactors.

- Hot-wall CVD reactors are usually tubular in form
  - Heating in HWCVD is accomplished by
  - Surrounding reactor with resistance element
- In typical cold-wall CVD reactors,
  - Substrates are directly heated
  - Inductively by graphite susceptors
  - Chamber walls are air or water-cooled

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